

Power-constrained hybrid BIST test scheduling in an abort-on-first-fail test environment

He, Zhiyuan; **Jervan, Gert**; Peng, Zebo; Eles, Petru Proceedings : DSD'2005 : 8th Euromicro Conference on Digital System Design : Architectures, Methods and Tools : Porto, Portugal, August 30 - September 3, 2005 / p. 83-86 : ill
<https://ieeexplore.ieee.org/document/1559782>